

R&D studies with resistive strip micromegas readouts

J. Galan¹

Also contributed to this work

D. Attie¹, J. Burners², A. Delbart¹, J. Derre,
I. Giomataris, E. Ferrer-Ribas¹, F. Jeanneau¹, R. de Oliveira²,
O. Maillard, P. Schune¹, A. Giganon¹

1. CEA Saclay

2. CERN Geneva

Outline

Work motivation

1. Problems of sparks in gas based detectors.
2. Spark-resistant micromegas prototypes made of resistive strips.

Signal propagation model

3. Model to characterize charge diffusion in resistive strips read-outs.
4. Results from charge diffusion at different conditions.

New prototype designs for testing

5. Prototypes to characterize resistive properties and charge diffusion.
6. Dedicated electronics to read-out resistive charge diffusion signal.

Sparks and discharges in gaseous detectors

One of the main problems in high gain gas based detectors is the **appearance of sparks**, and thus discharges in gas based detectors.

Sparks appear in the gaseous media when a critical high charge density is reached at the amplification region, given by the Raether limit (around 10^{7-8} electrons reached in the avalanche).

A simplified conceptual point of view is to understand this limit as the probability to generate new secondary avalanches. When the number of secondaries generated is higher than the number of primaries which generated the original avalanche then the process **is non-STOP (as soon as the amplification field is present)**.

The consequence is the discharge of the mesh and the drop of the voltage provided by the power supply. **Three main disadvantages:**

- 1) gain limitation.
- 2) deadtime increased due to the HV recovery time.
- 3) detector reduced lifetime.

Sparks and discharges in gaseous detectors

In order to reduce sparks resistive materials were introduced **First spark-protected detectors made of Resistive Plate Chambers (RPC).**

Nuclear Instruments and Methods in Physics Research A 431 (1999) 154–159

A spark-protected high-rate detector

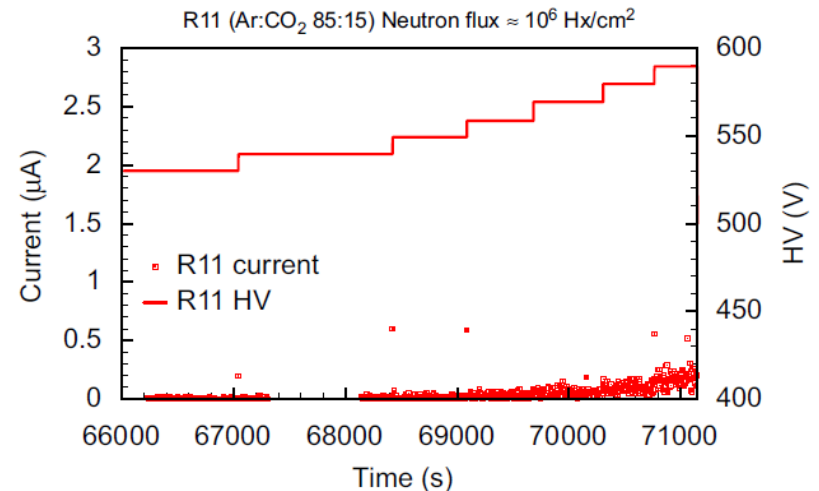
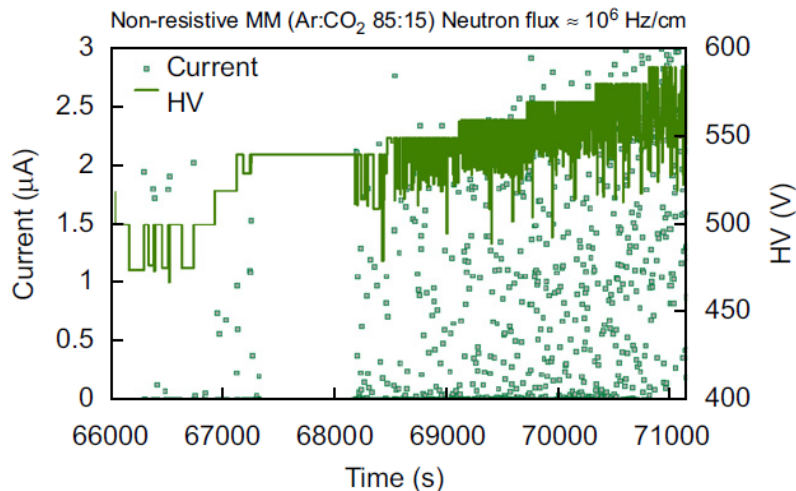
P. Fonte^{a,b,*}, N. Carolino^a, L. Costa^c, Rui Ferreira-Marques^{a,d}, S. Mendiratta^c,
V. Peskov^{e,1}, A. Policarpo^{a,d}

Recently this technique was also applied to Micromegas detectors by testing different resistive foils and strips topologies and proving good protection against sparks (development carried out within MAMMA collaboration for ATLAS muon chambers upgrades).

Nuclear Instruments and Methods in Physics Research A 640 (2011) 110–118

A spark-resistant bulk-micromegas chamber for high-rate applications

T. Alexopoulos^a, J. Burnens^b, R. de Oliveira^b, G. Glonti^b, O. Pizzirusso^b, V. Polychronakos^c,
G. Sekhniaidze^d, G. Tsipolitis^a, J. Wotschack^{b,*}



Resistive strip micromegas topology

The trick at the resistive based technologies is **that the field is lost during a time long enough (in the order of ns)** to allow charges drifting leave the gas.

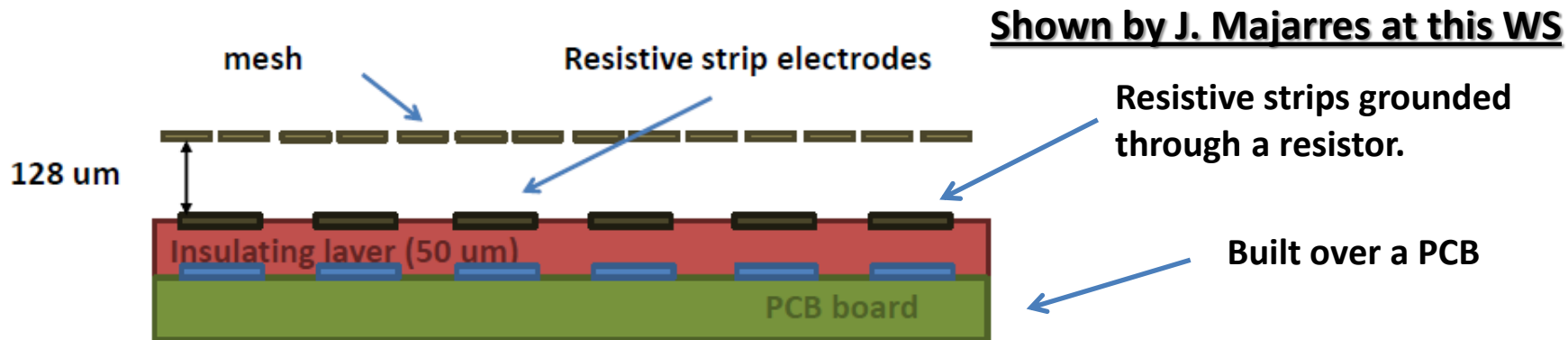
The main advantages

The spark does not evolve to its final state, the total discharge charge is well reduced and the power supply **voltage at the mesh is not affected**.

Field is lost only locally.

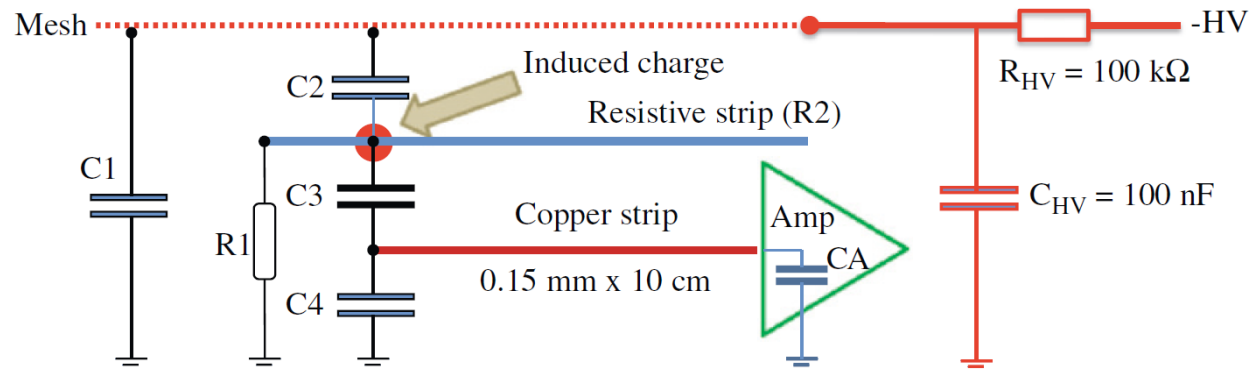
This leads to increased detector lifetime and reduced deadtime

One of the topologies that better performance presented during tests at SPS beam at CERN



A simplified electronic model to study resistive strip read-outs.

The same publication mentioned before gives the same **equivalent electronic model** which involves a resistive strip. Can be considered as the simplest model to take into account for a base study.



The present work is partially inspired on the previous work of Dixit & Rankin, where they obtain an analytical approach to the charge dispersion on a bi-dimensional resistive foil and the induction to electrode pads through an insulation layer. Obtaining spatial read-out capabilities.

Nuclear Instruments and Methods in Physics Research A 566 (2006) 281–285

Simulating the charge dispersion phenomena in Micro Pattern Gas Detectors with a resistive anode

M.S. Dixit^{a,b,*}, A. Rankin^a

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Signal propagation model

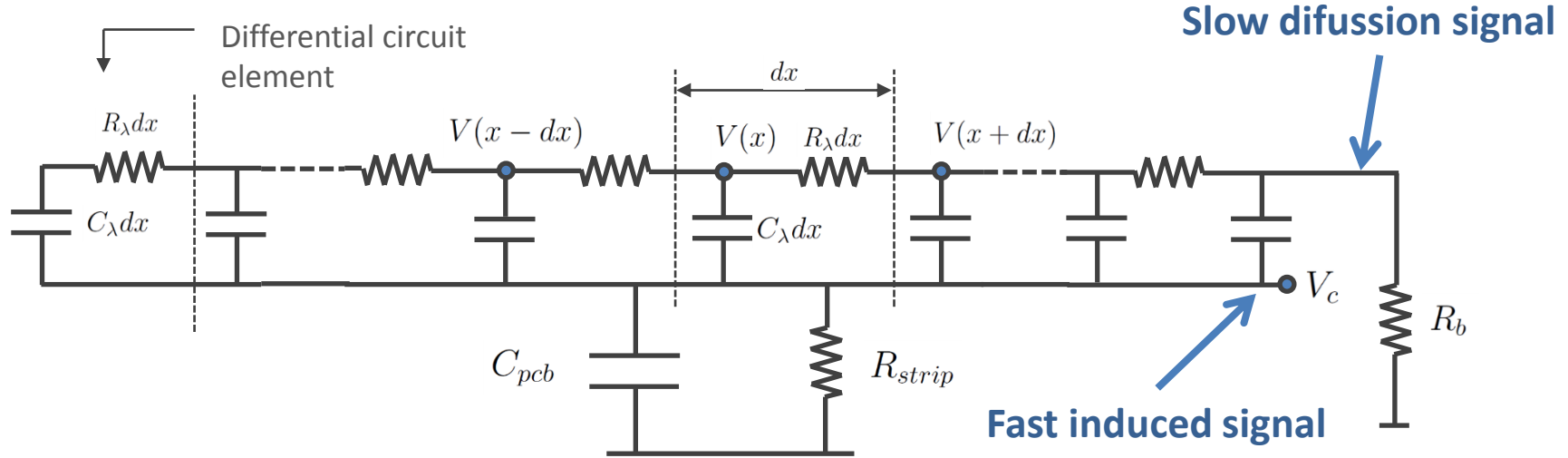
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Resistive strip model to calculate charge diffusion

The most simplified model of a resistive strip is obtained by replacing the strip by a transmission line.



The propagation of the signal generated by a charge deposited at the resistive strip surface is described by the following expression.

$$\frac{\partial^2 V(x, t)}{\partial x^2} = C_\lambda R_\lambda \frac{\partial (V(x, t) - V_c(t))}{\partial t} + R_\lambda \frac{\partial \rho(x, t)}{\partial t}$$

Which is moreover bounded by the electronic read-out connection

$$\frac{dV_c(t)}{dt} = \frac{C_\lambda}{C_{pcb} + x_L C_\lambda} \int_0^{x_L} \frac{\partial V(x, t)}{\partial t} dx - \frac{V_c(t)}{(x_L C_\lambda + C_{pcb}) R_{strip}}$$

These equation are solved by spatial discretization (standard and very well known method)

$$\frac{dV_j}{dt} = \frac{1}{\tau_\lambda \delta x^2} (V_{j+1} - 2V_j + V_{j-1}) + \frac{dV_c}{dt} - \frac{1}{C_\lambda} \frac{d\rho_j}{dt}$$

Which leads to a set of coupled differential equations

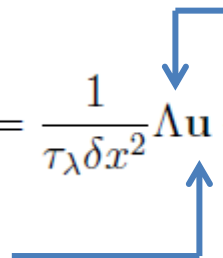
$$\frac{d}{dt} \begin{bmatrix} v_1 \\ \vdots \\ v_n \end{bmatrix} = \frac{1}{\tau_\lambda \delta x^2} \begin{bmatrix} -2 & 1 & & 0 \\ 1 & -2 & 1 & \\ & \ddots & \ddots & \ddots \\ & & 1 & -2 & 1 \\ 0 & & & 1 & -1 \end{bmatrix} \begin{bmatrix} v_1 \\ \vdots \\ v_n \end{bmatrix} + \frac{1}{\tau_\lambda \delta x^2} \begin{bmatrix} v_o \\ 0 \\ \vdots \\ 0 \end{bmatrix} - \frac{1}{C_\lambda} \frac{d}{dt} \begin{bmatrix} \rho_1 \\ \vdots \\ \rho_n \end{bmatrix} + \frac{dV_c}{dt} \begin{bmatrix} 1 \\ \vdots \\ 1 \end{bmatrix}$$

Which after some transformations allow to solve a set of N undependent equations.

Diagonal matrix

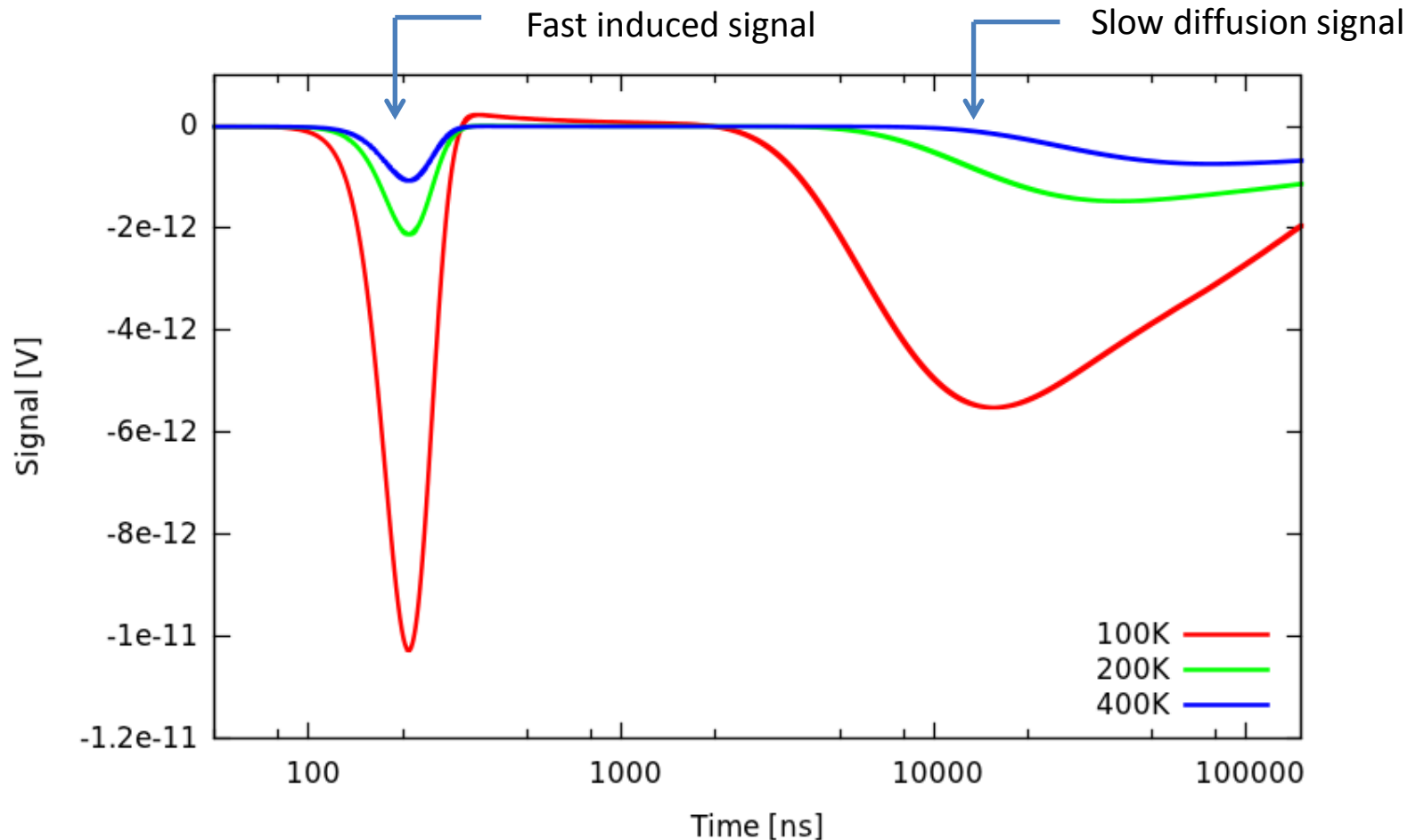
$$\frac{d\mathbf{u}}{dt} = \frac{1}{\tau_\lambda \delta x^2} \mathbf{\Lambda} \mathbf{u} + \frac{1}{\tau_\lambda \delta x^2} \mathbf{\chi} \mathbf{v}_o - \frac{1}{C_\lambda} \mathbf{\chi} \frac{d\rho}{dt} - \frac{\xi V_c}{C_\lambda R_{strip}} \mathbf{\chi} \mathbf{b}$$

Transformed potential



Current evolution at the boundary resistor R_b for different resistivity values (Logarithmic time scale)

The model shows a fast induced signal which is the common read-out signal, and additionally a second signal due to charge diffusion through the resistive strip.



Different simulations set-ups

Simulations at different boundary resistors values.

$$R_{\lambda} = 100\text{k}/\text{mm}$$

$$C_{\lambda} = 0.2\text{pF}/\text{mm}$$

$$R_b = 250\text{K}, 2.5\text{M}, 5\text{M}, 10\text{M}$$

Simulations at different strip resistivities

$$R_{\lambda} = 50, 100, 200 \text{ k}/\text{mm}$$

$$R_b = 10\text{M}$$

$$C_{\lambda} = 0.2\text{pF}/\text{mm}$$

Simulations at different strip capacitances

$$C_{\lambda} = 0.05, 0.2, 1 \text{ pF}/\text{mm}$$

$$R_b = 10\text{M}$$

$$R_{\lambda} = 100 \text{ k}/\text{mm}$$

Simulations at different signal positions

$$\Delta x = 0.5 \text{ mm}$$

$$C_{\lambda} = 0.2\text{pF}/\text{mm}$$

$$R_{\lambda} = 100 \text{ k}/\text{mm}$$

$$R_b = 5\text{M}$$

Cluster size simulations 100 μm

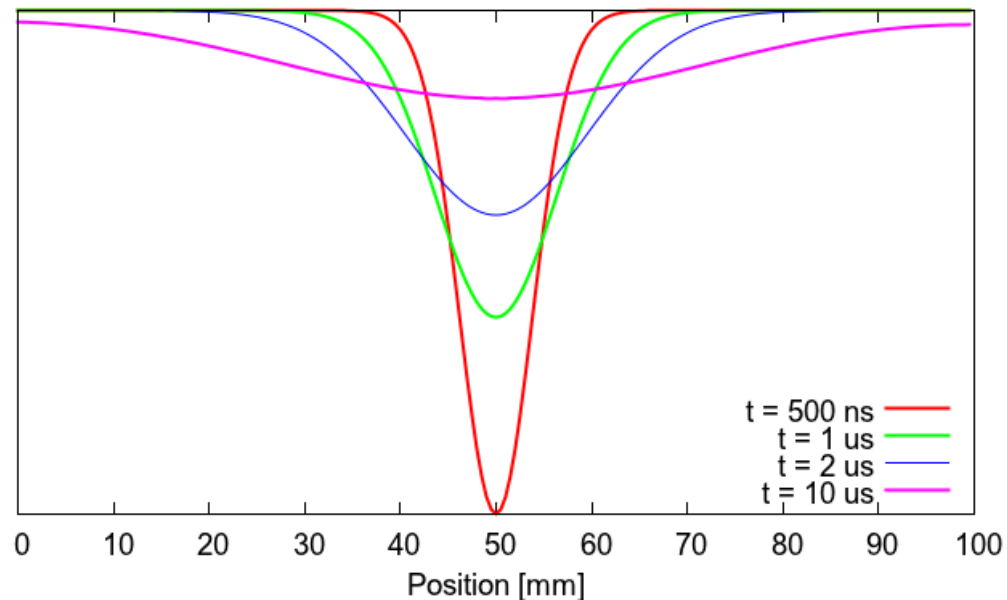
Contrary to fake intuition signal is not dependent on transversal diffusion

Charge diffusion at different periods of time

A gaussian charge signal is introduced at the center of the detector.

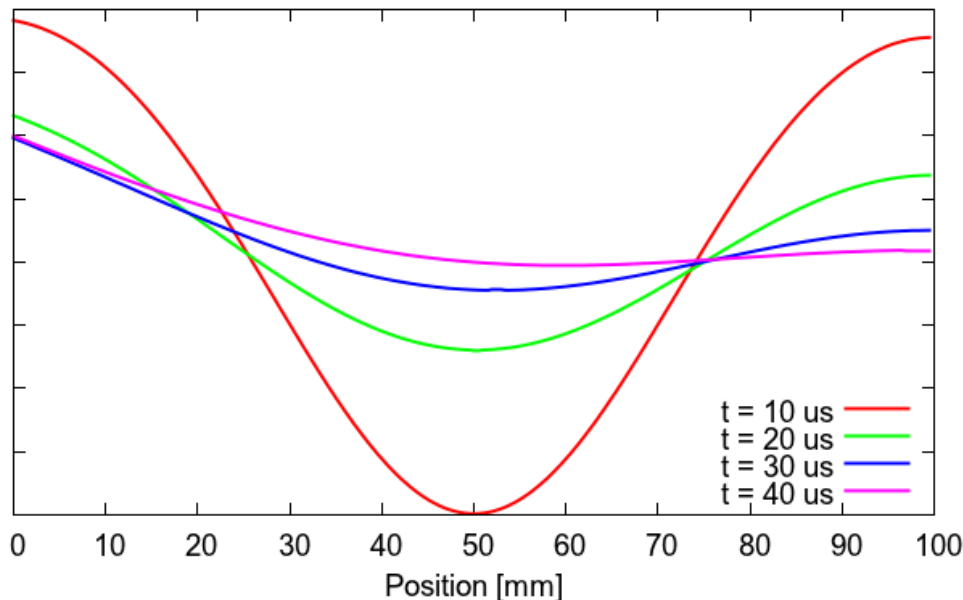
With highest value at 200ns and a sigma of 50ns distributed in few mm.

First time steps



GND

Last time steps

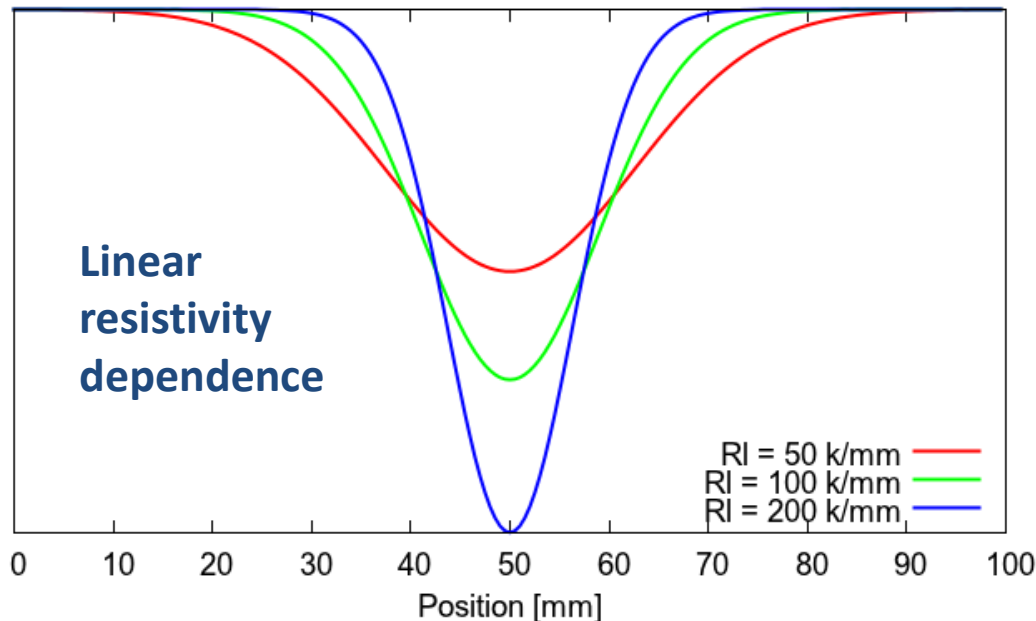
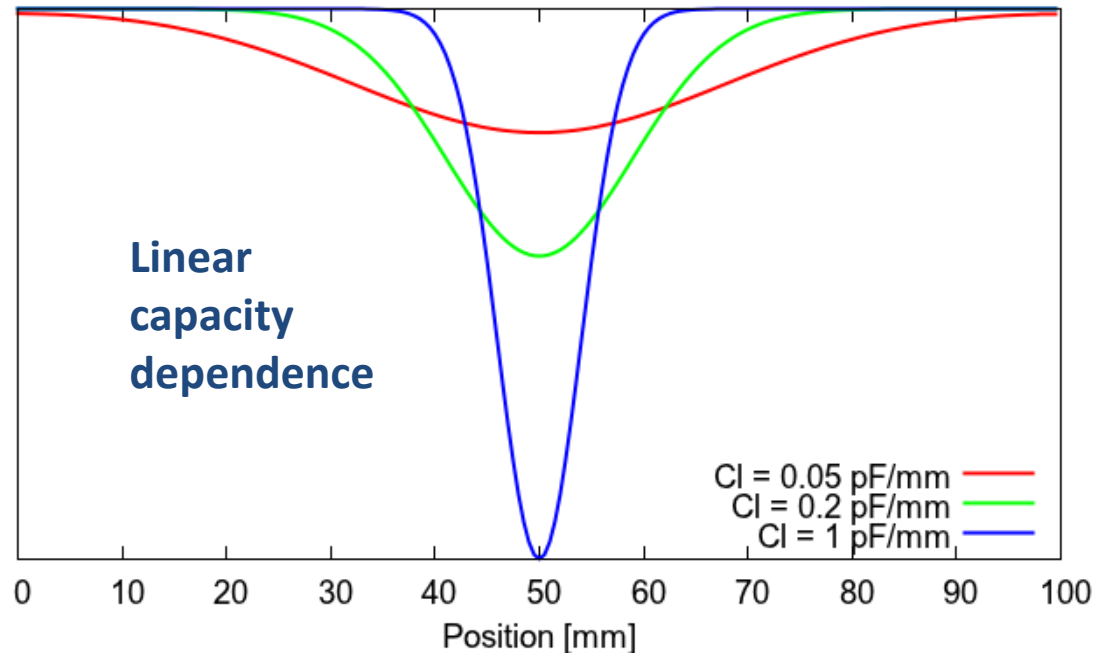


The effect of charges drifting to ground it is observed at the latter time steps.

Charge diffusion at different resistivities and capacitances

For the same input signal the charge spread at different resistivities and capacitances values can be evaluated.

These results correspond to the charge spread after 1 μ s diffusion



As expected higher capacitance and higher resistivity

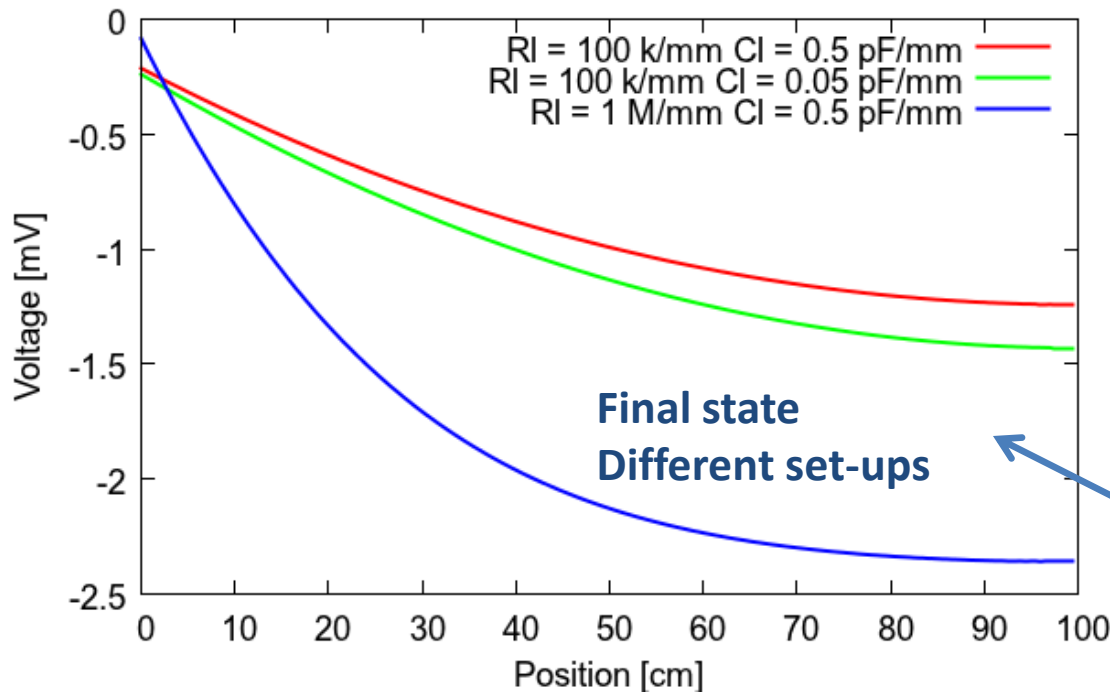
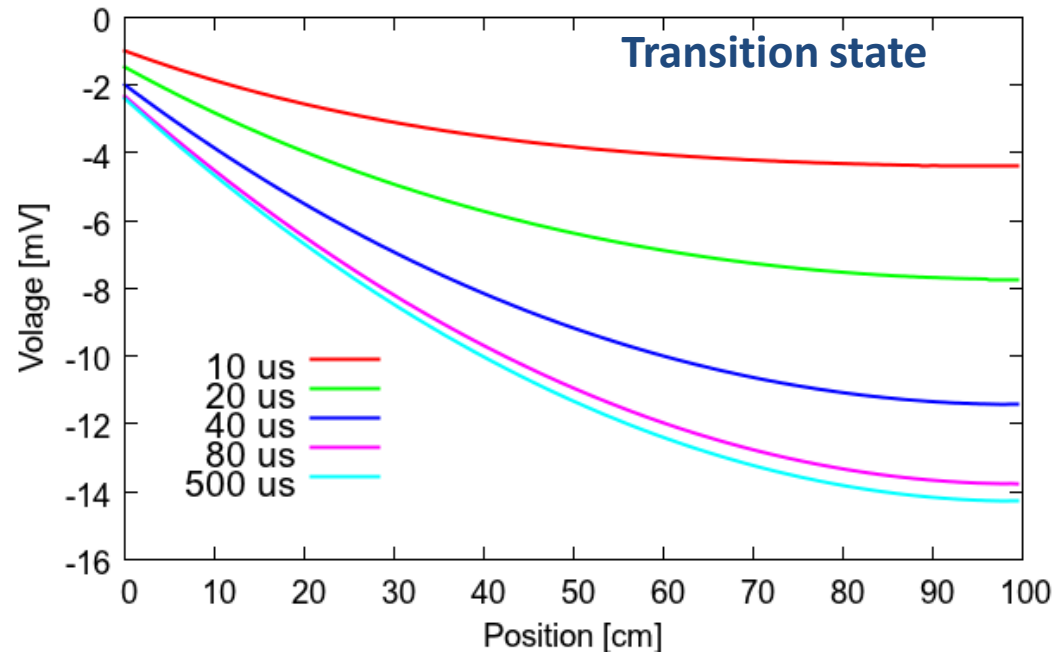


lower charge diffusion

Simulating homogeneous illumination

Instead of using a Gaussian signal an homogeneous current along the resistive strip is introduced

Rate = 100 kHz
Gain = 10000
Primary electrons = 300



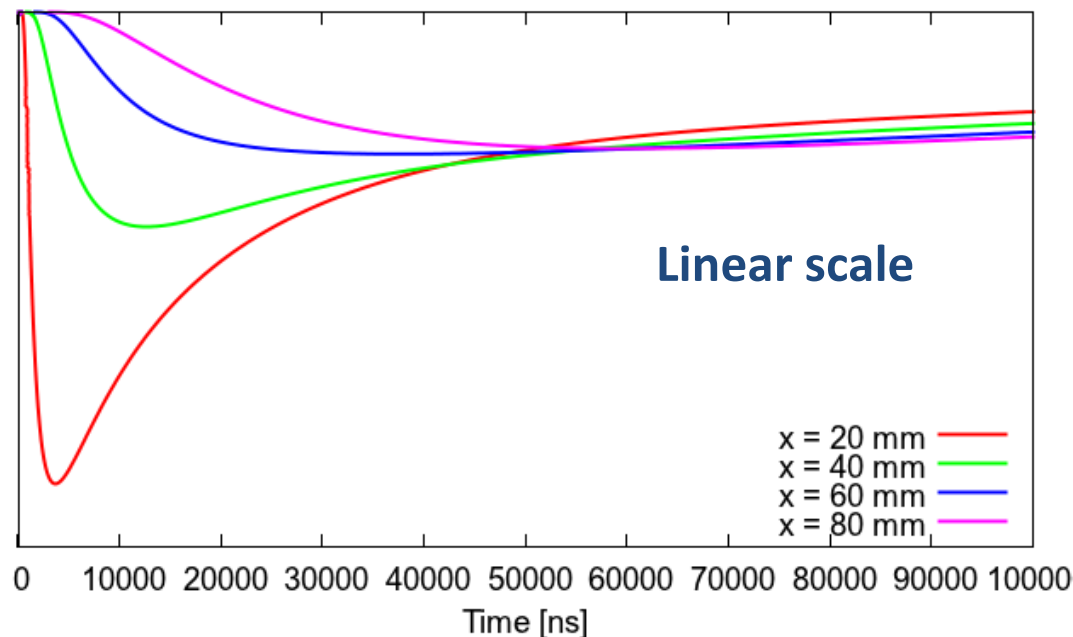
The resistive foil is charged-up and it could lead to gain inhomogeneities

Relation with resistivity and capacitance at the final state.

Obtaining a signal through resistive at different positions

The **current at the boundary** resistor is plotted versus time for different positions every 0.5 mm **showing different pulse-shapes and delays.**

Closer to the ground higher is the signal and the most dangerous for read-out electronics.



Gaussian current signal
at 200 ns and sigma 50 ns

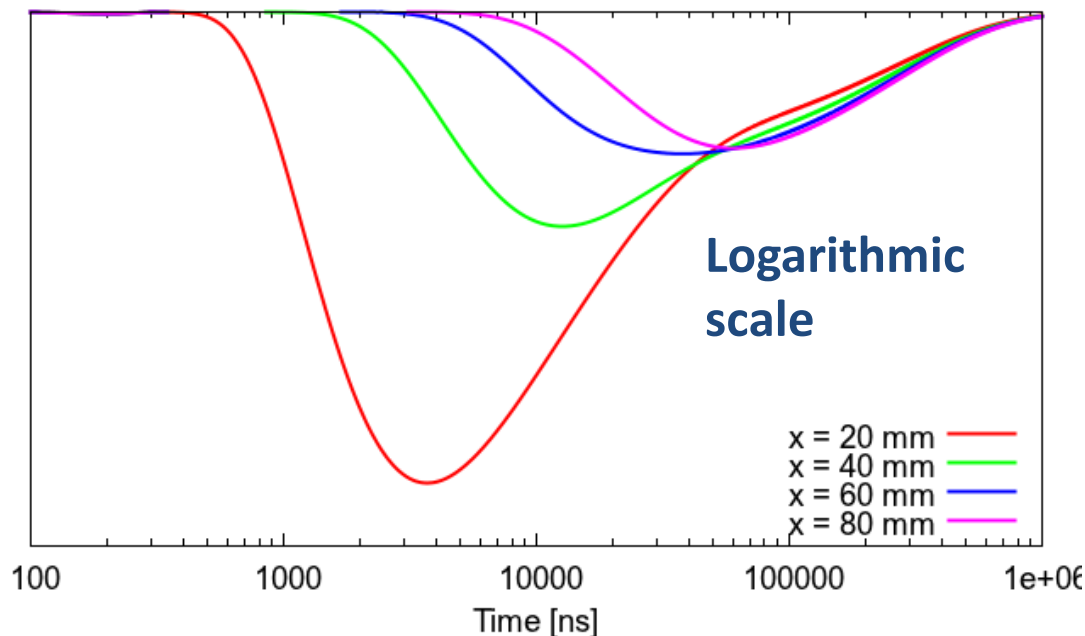
Resistive strips parameters

$RI = 100 \text{ k}/\text{mm}$

$CI = 0.2 \text{ pF}/\text{mm}$

$Rb = 5M$

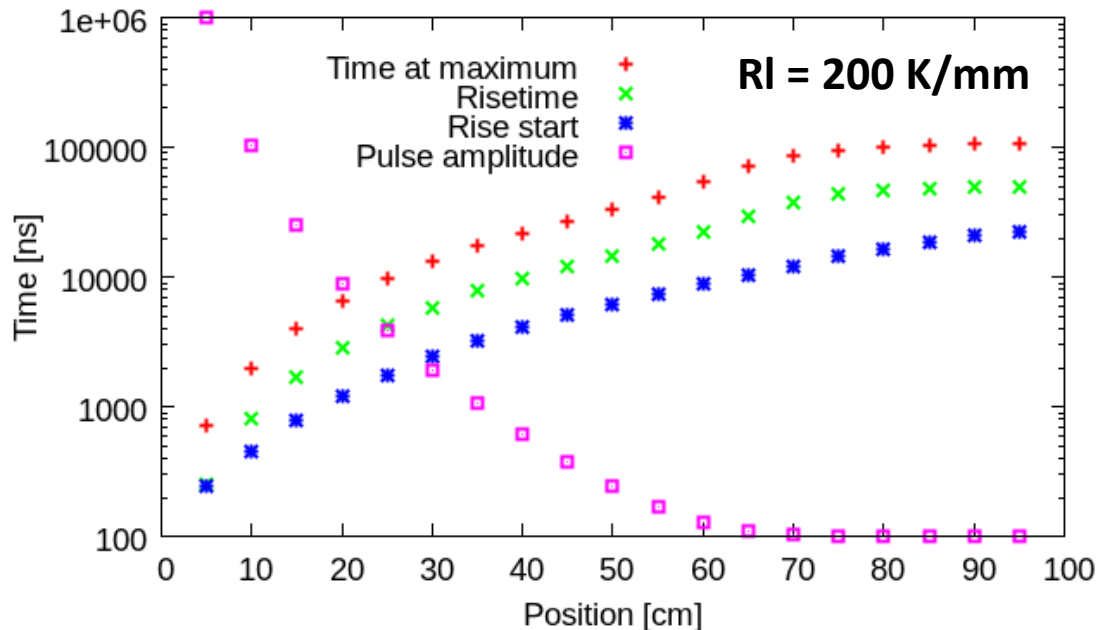
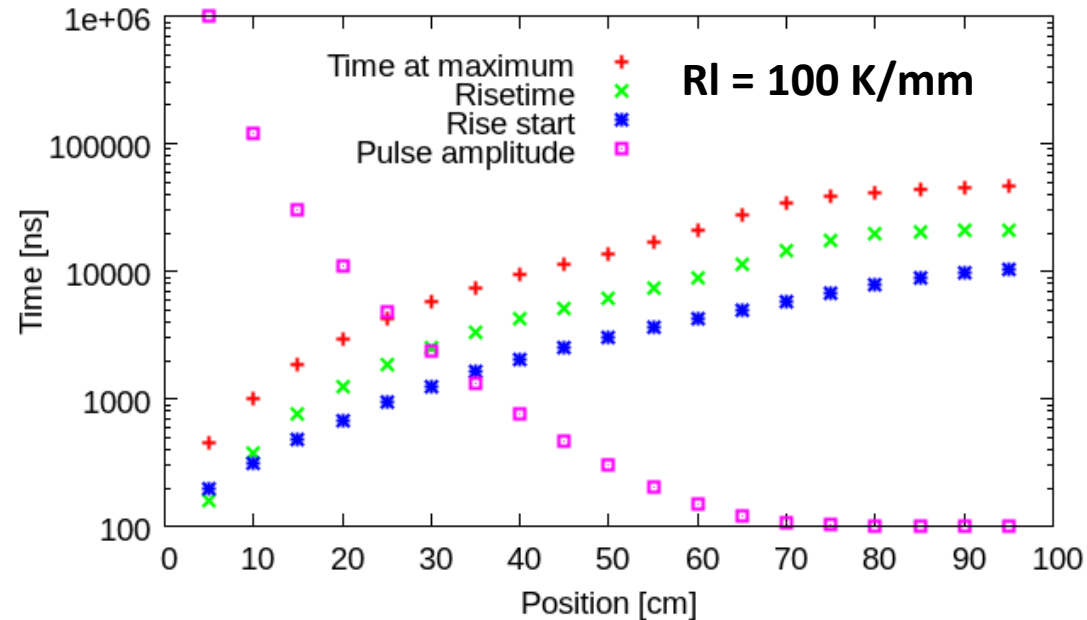
Logarithmic
scale



Pulse properties for different event positions

Two resistivities shown at
fixed linear capacitance
and boundary resistor

$Cl = 0.2 \text{ pF/mm}$
 $Rb = 10 \text{ M}$



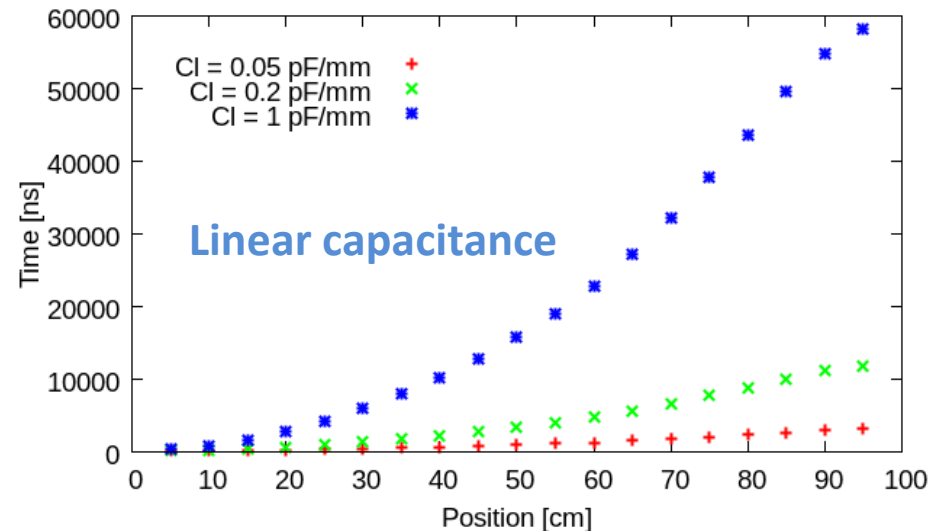
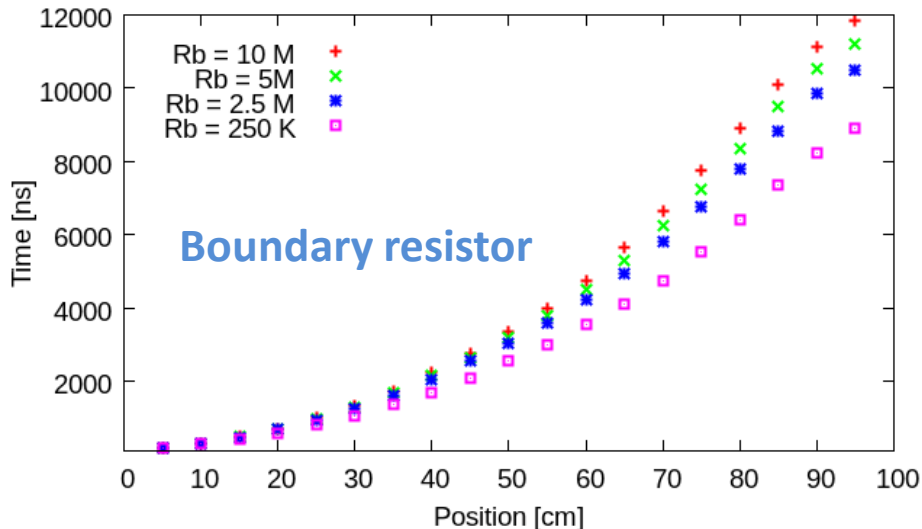
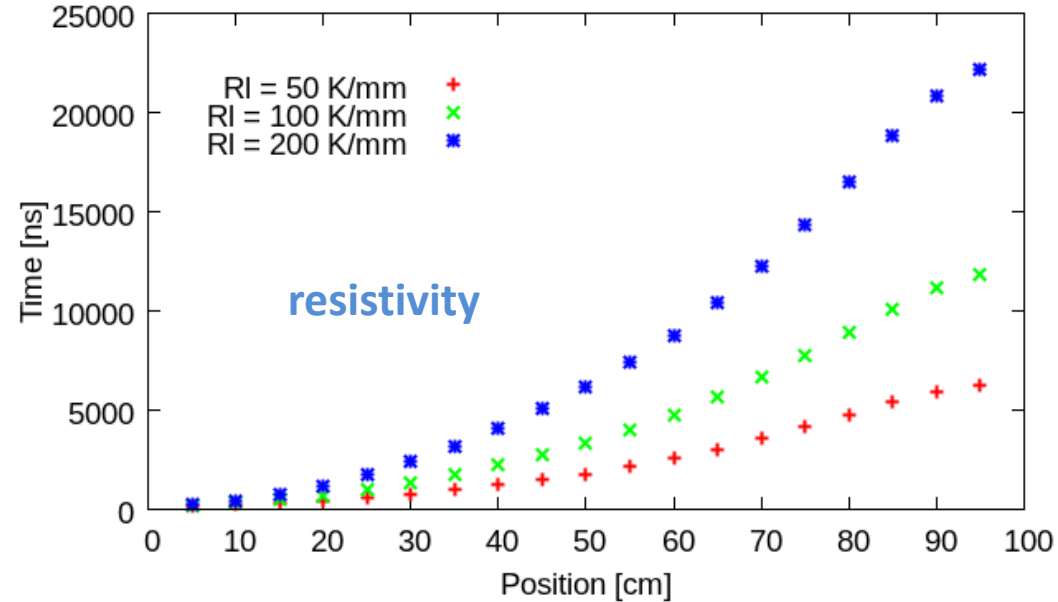
Pulse properties: risetime,
width and rise-start changes
along the resistive strip
length.

Opens the possibility to use
these properties for event
position recognition

Risetime-start delay for different resistive strip model parameters

Signal delay is obtained for different linear resistivities, linear capacitances and boundary resistor values.

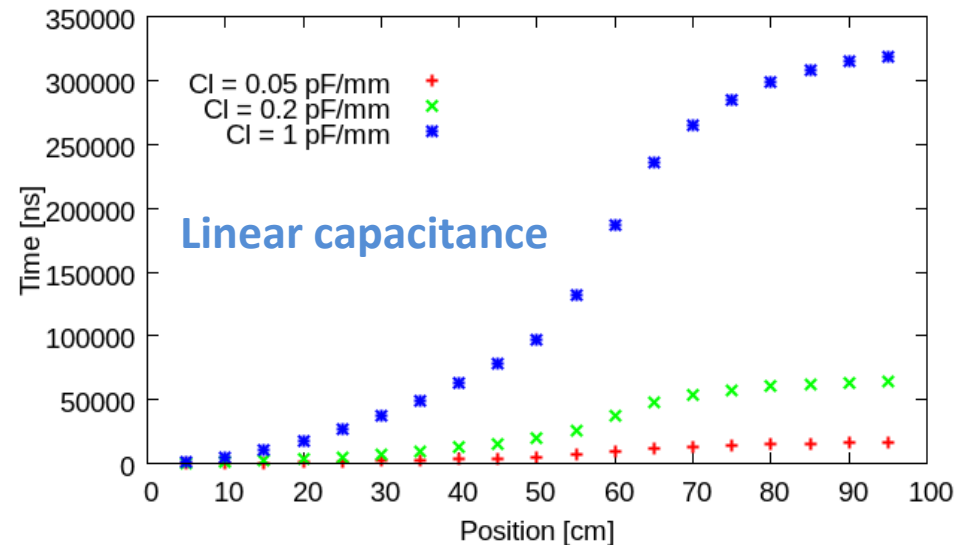
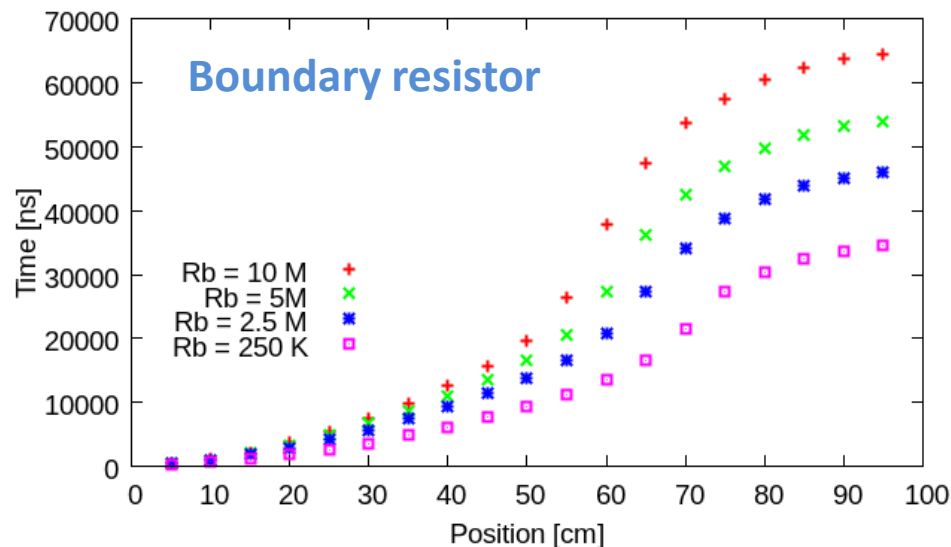
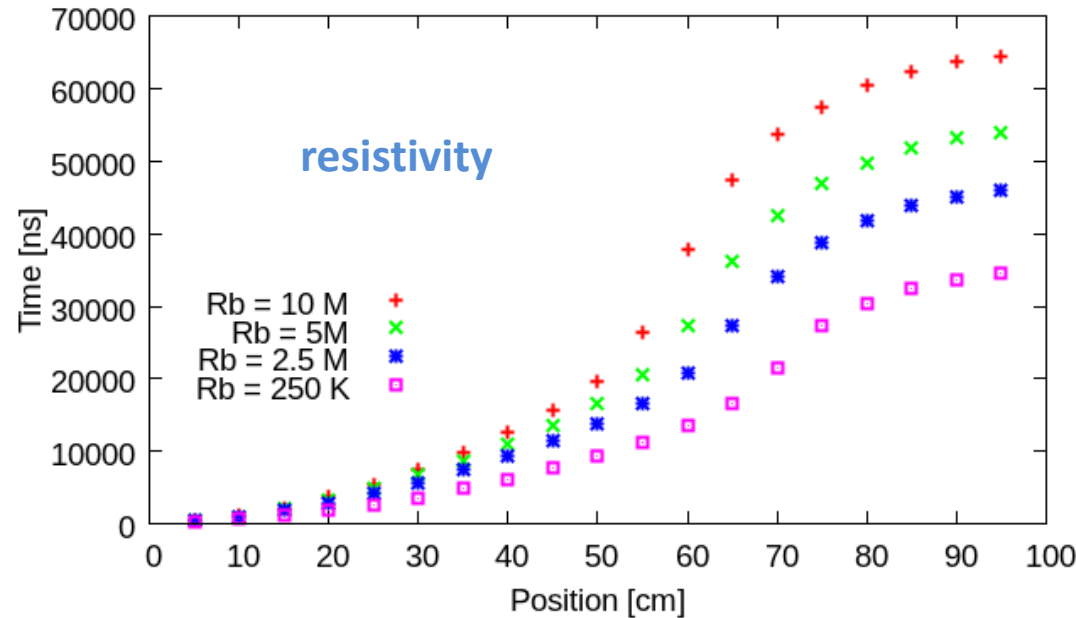
Signal shows NO big delay dependency with boundary resistor.



Maximum peak delay with event position

Maximum peak delay is obtained for different linear resistivities, linear capacitances and boundary resistor values.

Linear capacitance is crucial in the time delay.



Future studies related with resistive strip read-out

Use a beam current at different positions to study gain **unhomogeneity** due to dependency on charge distribution.

Introduce gain dependency (through Townsend parameters) in the description of the input current, and calculate **gain relation with input current**.

Change the potential of V_c to different fixed values to check **effect on the gain**, tests at different V_c values to be done experimentally.

Study the **effect of the strip length in gain homogeneity**.

Resistive strip model is implemented in C code allowing to integrate a future more complex simulation (with i.e. Garfield, neBEM, etc)

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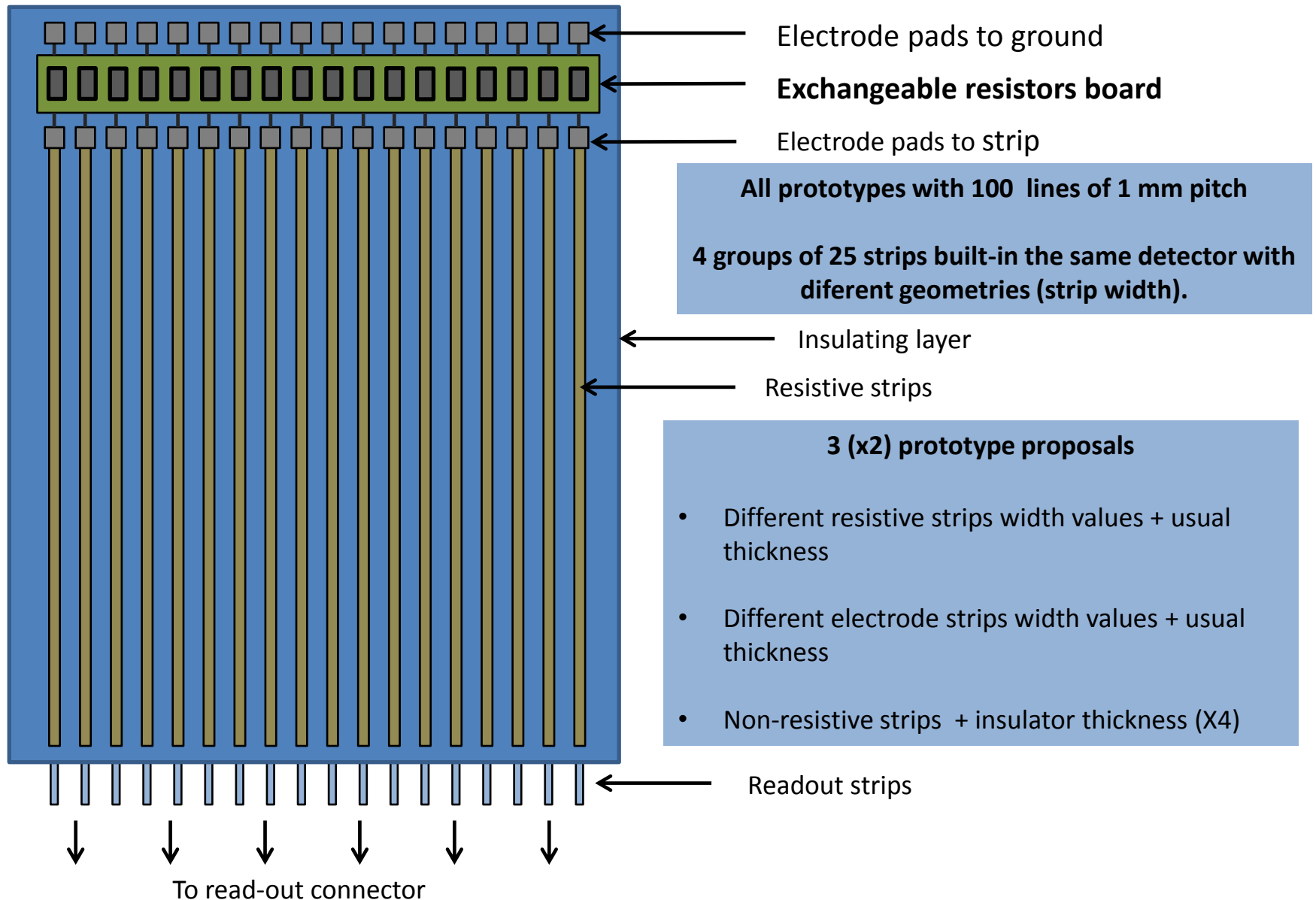
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General resistive prototypes

1-D readout (2-D capabilities?)

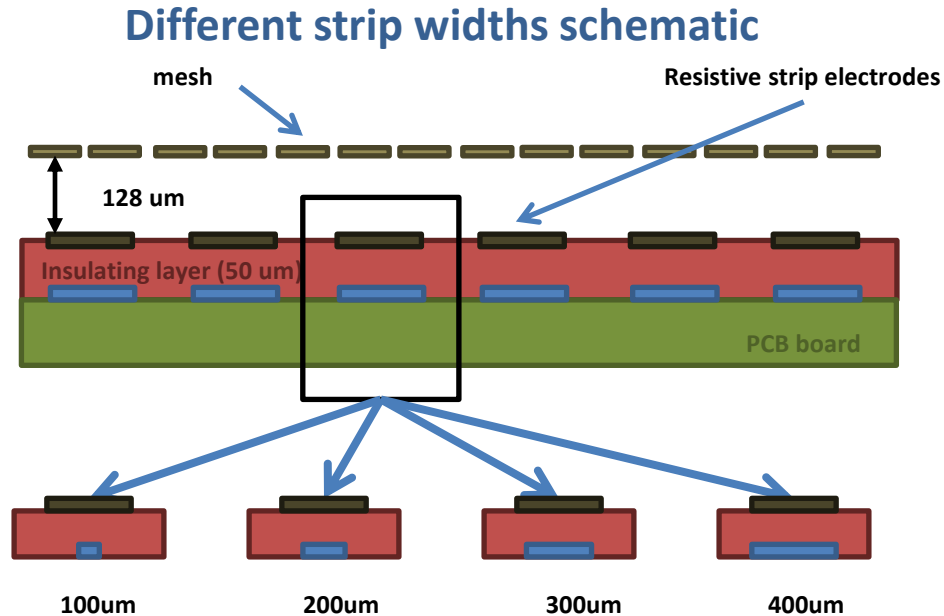


General resistive prototypes

1-D readout (2-D capabilities?)

Prototypes designed and built at
CERN PCB Workshop

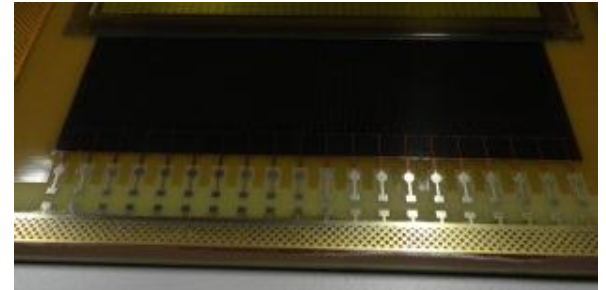
R. de Oliveira, J. Burners
based on MAMMA prototypes



Microscope picture



Resistive strips
read-out pads
picture



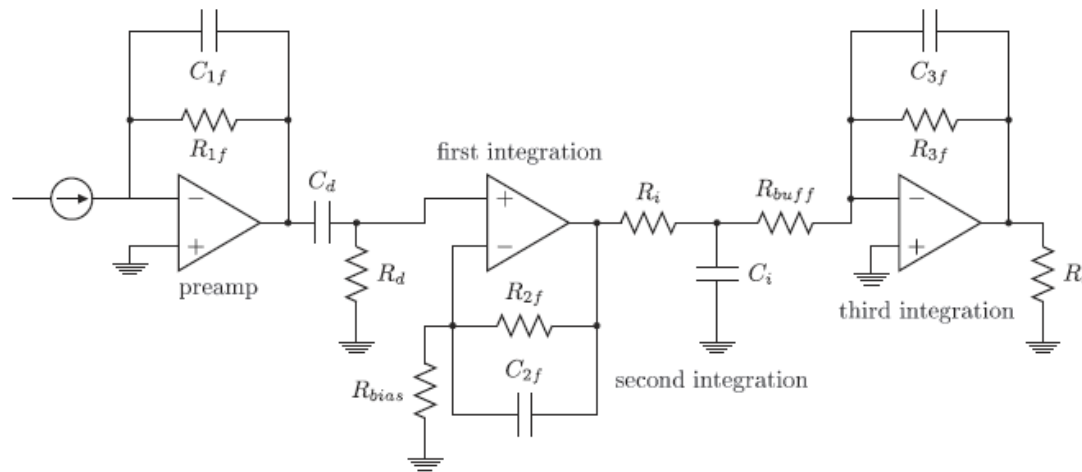
Electronic read-out to couple to high-impedance

Nuclear Instruments and Methods in Physics Research A 646 (2011) 118–125

Longitudinal resistive charge division in multi-channel silicon strip sensors

Jerome K. Carman^a, Vitaliy Fadeyev^a, Khilesh Mistry^a, Richard Partridge^b, Bruce A. Schumm^{a,*}, Edwin Spencer^a, Max Wilder^a

Preamplification stage + 3 integration stages.



“Optimum signal to noise ratio is given when the number of integration stages approaches infinity, **with a total integration time equal to the differentiation time**”. Three stages are chosen just for simplicity.

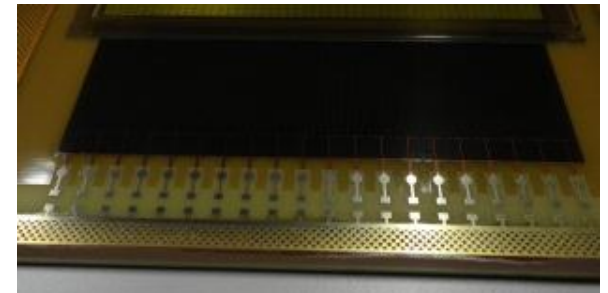
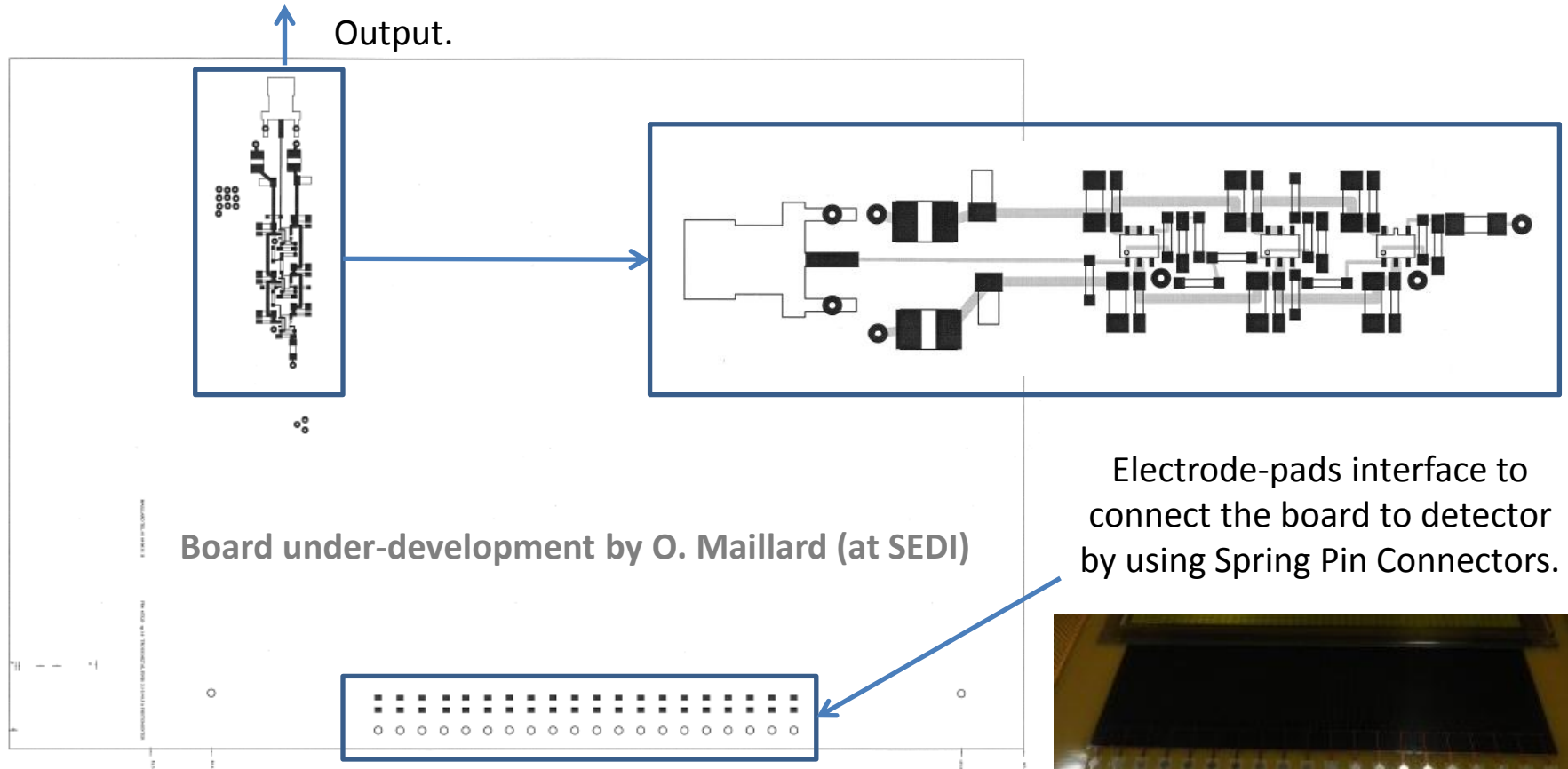
Thus, once the integration time is constrained it is also constrained the differentiation time.

Shorter shaping times than signal duration -> charge will be lost
On the other hand, parallel noise is proportional to the shaping time.
Shaping time should be a compromise and thus must be optimized.

PCB read-out board

In order to read-out the resistive read-out signals at each line (20 lines) a PCB board is under design at SEDI (O. Maillard).

In principle SMA connector will be used in order to read-out with scope.
Future solution to read-out 20 lines to be implemented.



Summary, conclusions and future work.

Is a fact that **resistive technology** (RPC and rMPGD) **do prevent sparking** processes at the detector.

In the framework of the last resistive micromegas detectors produced for MAMMA, a **simplified resistive-strip model** was used to derive results in different detector conditions.

First results show

- possible inhomogeneity's in the gain due to charge diffusion.
- Pulse-shape dependency with position.

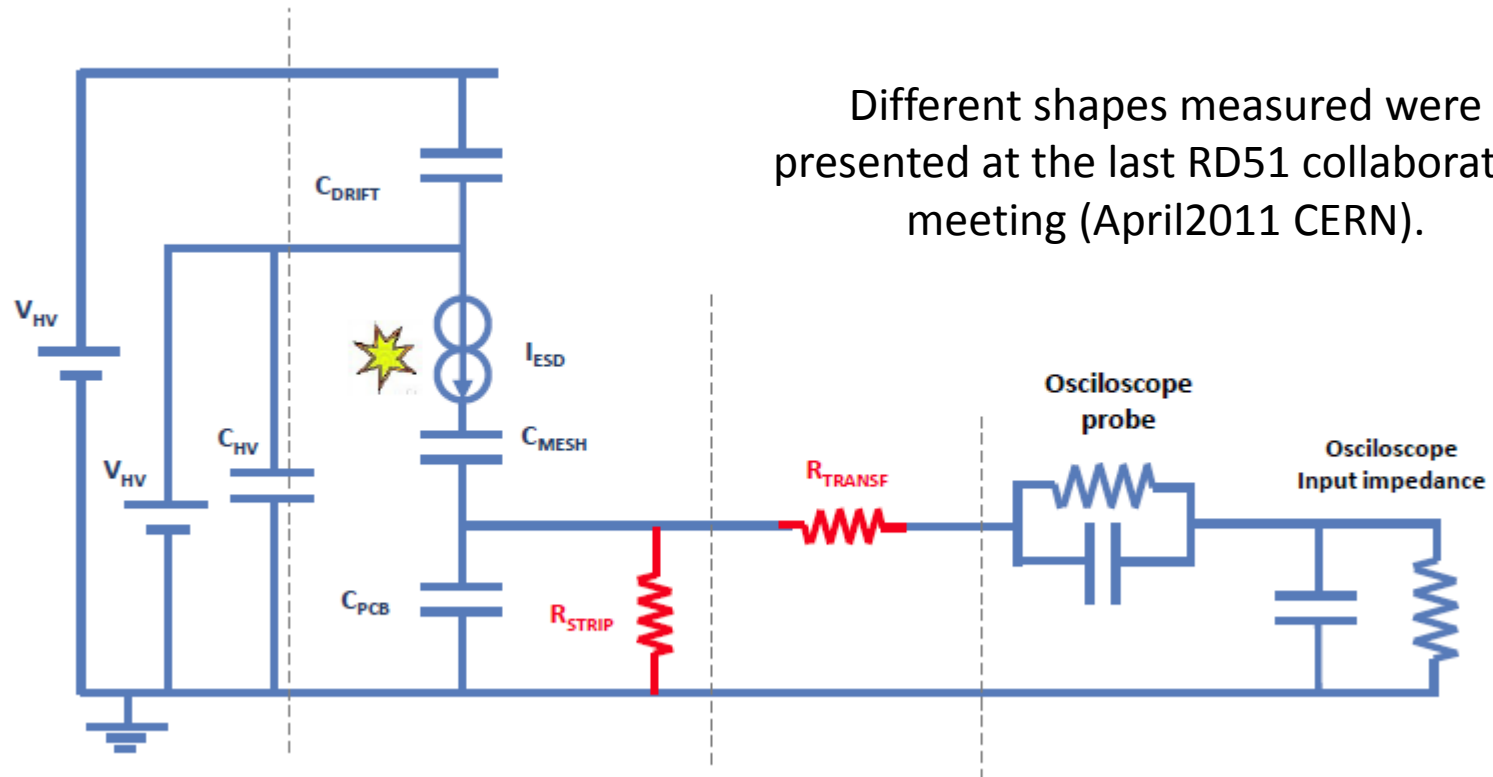
Future results

- Gain dependency with particle flux rate
- Gain versus mesh voltage curve for a fixed current

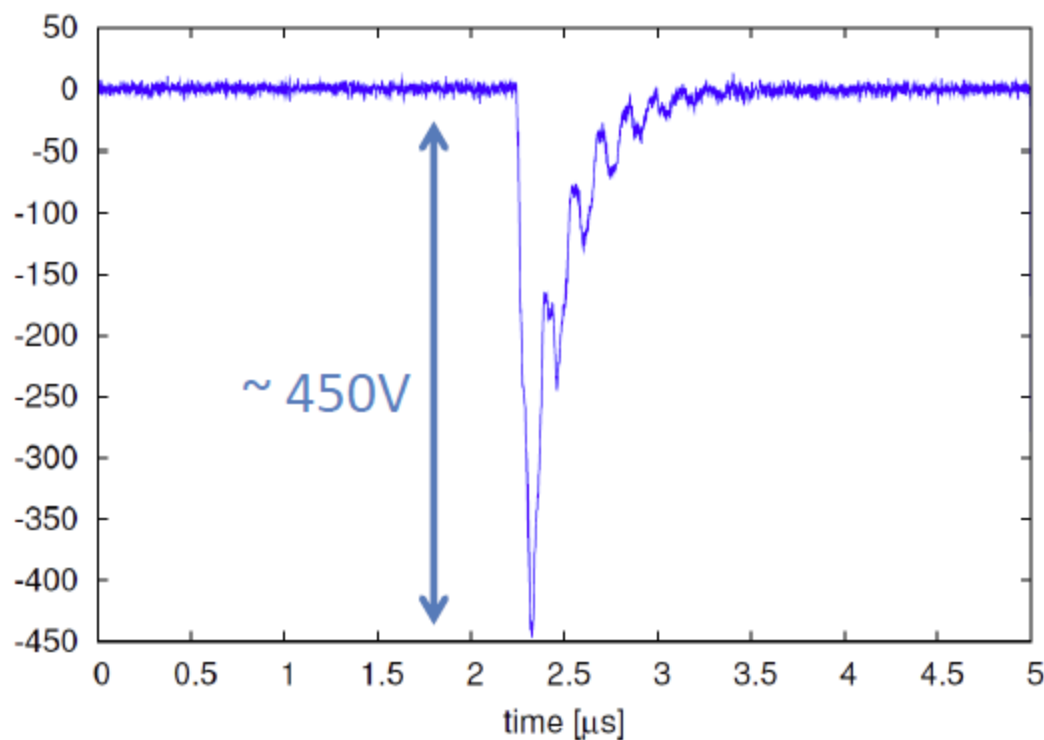
Prototypes ready for testing, characterization of resistive propagation will allow to measure signal delay and charge produced by different kind of events, included sparks.

3. Transient measurement at different connection schemes

Transient measurements were taken at different connection schemes.



Interesting oscillations and shapes recorded which depend on the read-out configuration.



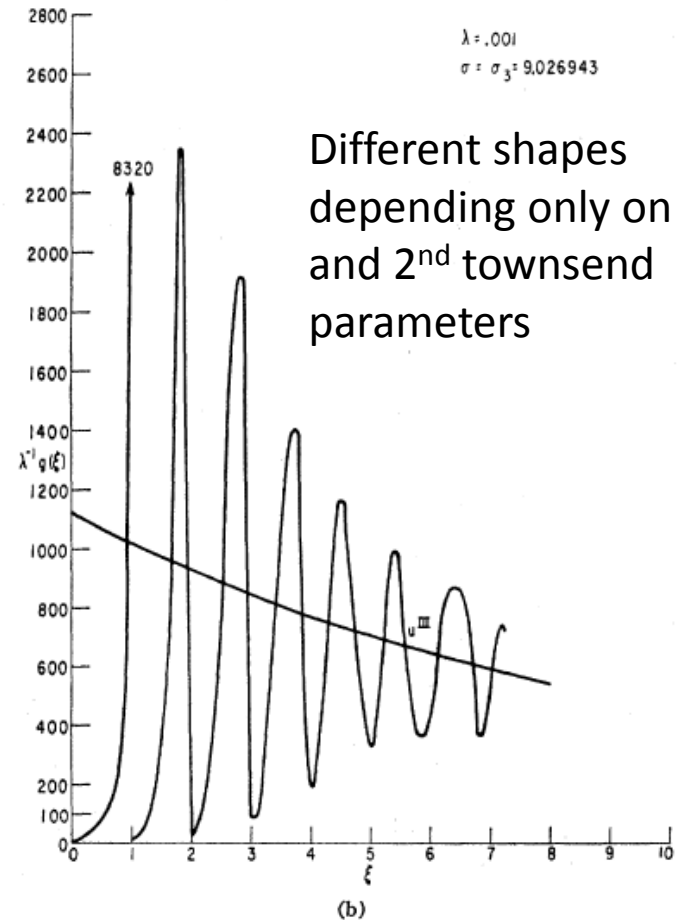
“Transient analysis of the townsend discharge”, P. Auer

Such oscillations could be related with the ion transient time in the amplification gap.

Theoretical oscillation periodicity is given by the transient time.

In order to proof such thing one can check the periodicity dependency with high voltage and gas mixture.

Theoretical calculation



Planning to extend the measurements presented at RD51 by using new configuration schemes including resistive type detectors.